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Dawson, John, Arien, Yoeri and Pissoort, Davy (2019) Overview of the P2715 WG - IEEE Guide for the Characterization of the shielding effectiveness of planar material: Overview of Planar Shielding Results and Methods. In: UNSPECIFIED.

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Overview of Planar shielding results and methods

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With results and images from:

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A Bohbe, CISCO Systems, US

F Leferink, Thales, NL

J Janukiewicz, & Z Joskiewicz, Wrocław University of Science and Technology, PL

D Inman, Parker Chomerics, US

V Gkatsi & E Tourounoglou, Aristotle University of Thessaloniki; A Roc'h, Eindhoven University of Technology; and

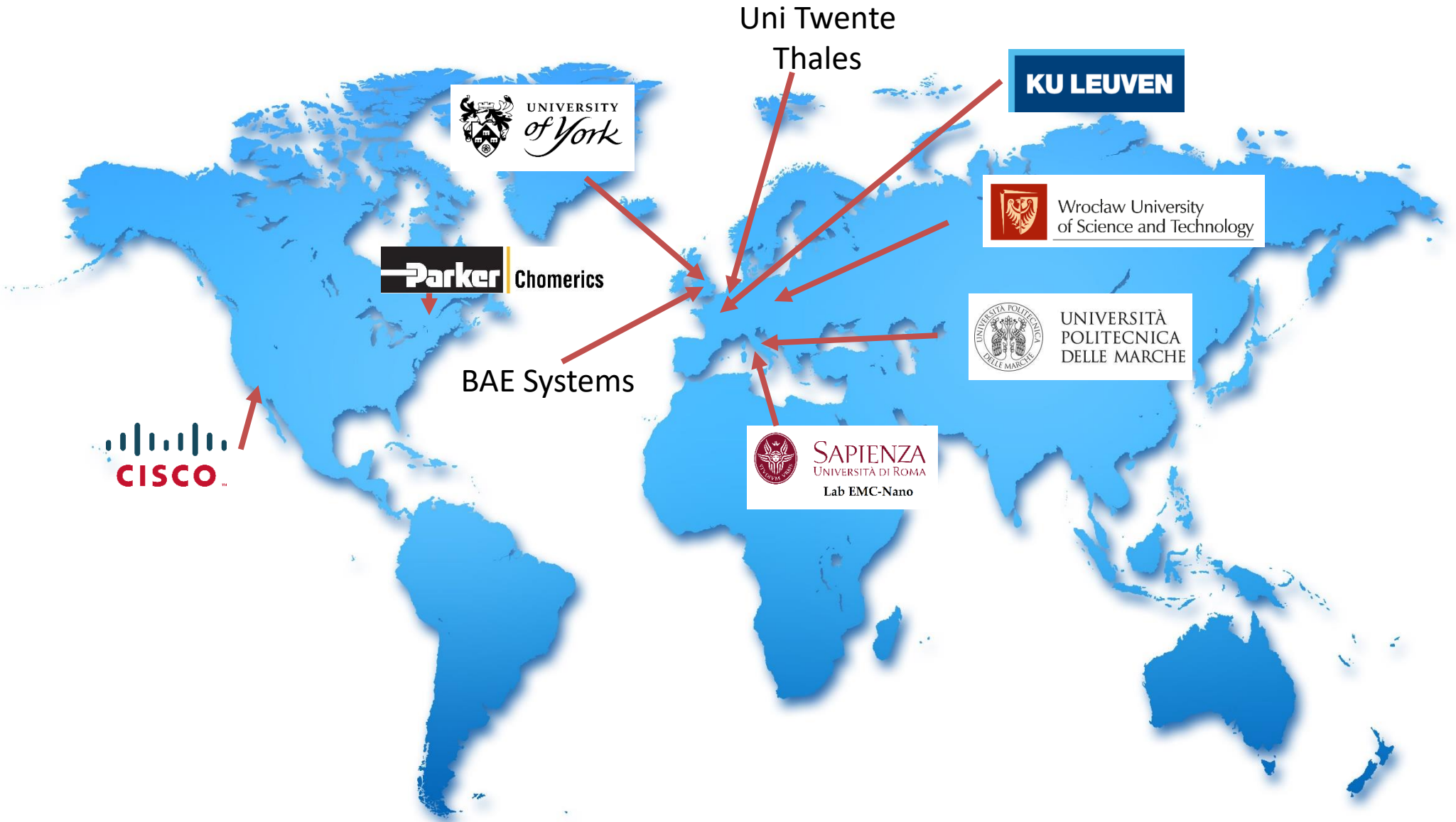
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Dawson, J.; Arien, Y. & Pissoort, D. , "Overview of the P2715 WG - IEEE Guide for the Characterization of the shielding effectiveness of planar material: Overview of Planar Shielding Results and Methods" , Electromagnetic Compatibility (EMC), 2019 IEEE International Symposium on , 2019

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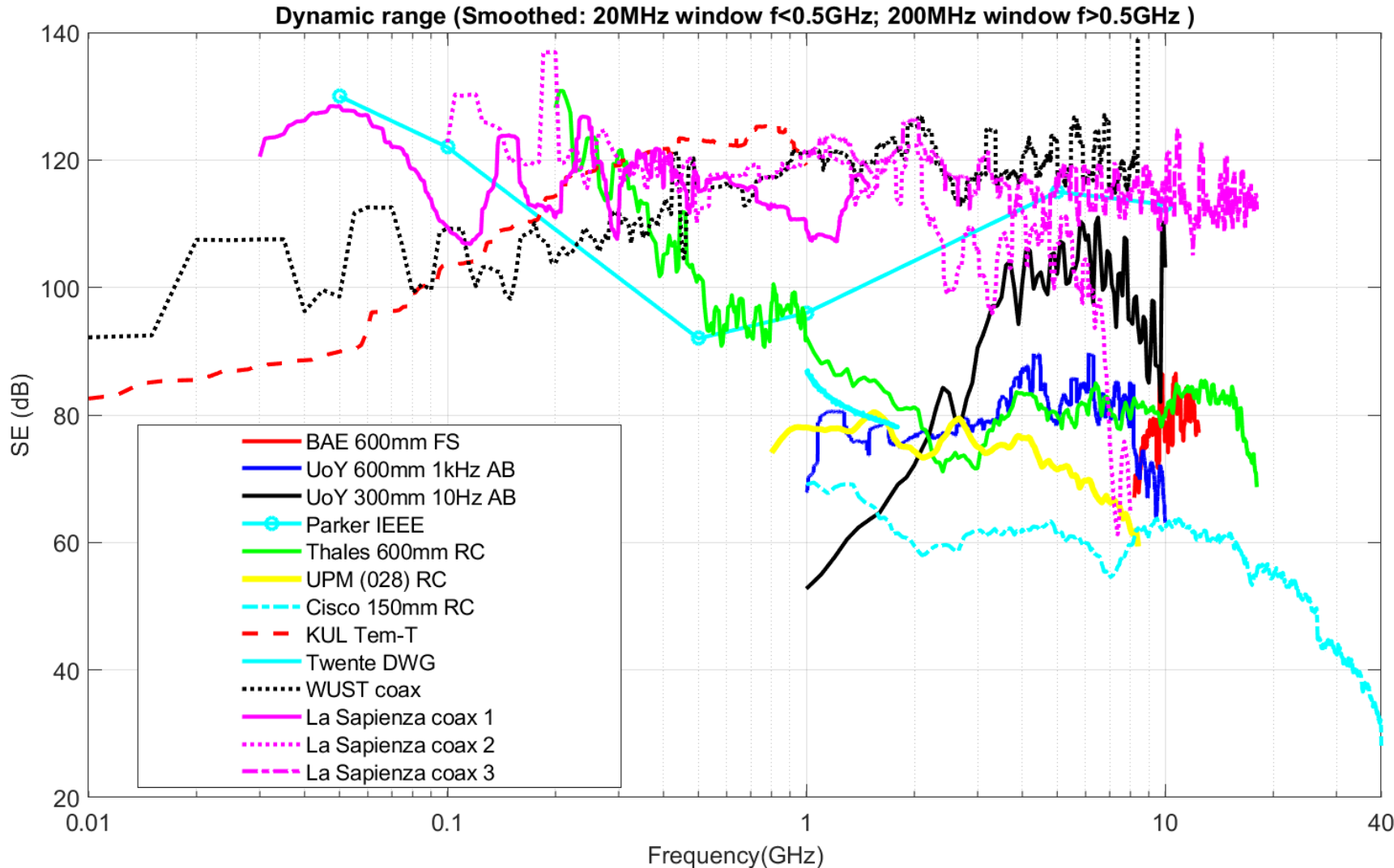
So what's the difference ?

- Standard method ?
- Dynamic range
- Frequency range
- Sample preparation
- Anisotropic materials
- Physical size
- Accuracy of results
- Equipment required
- What is measured

Standards

- Standardized SE measurement techniques
 - ASTM D4935-10: Standard Test Method for Measuring the Electromagnetic Shielding Effectiveness of Planar Materials
 - valid over a frequency range of 30 MHz to 1.5 GHz
- SE measurement techniques derived from standardized techniques
 - IEEE 299: Standard method for measuring the effectiveness of electromagnetic shielding enclosures
 - IEC 61000-4-21: Testing and measurement techniques – Reverberation chamber test methods
 - (Nested) reverberation chambers
 - Vibrating Intrinsic Reverberation Chamber (VIRC)

Dynamic range



Comparing the dynamic range reported by the participating labs

- The dynamic range depends on the measurement instruments and settings as well as the method.
- The coax method tends to have the best dynamic range as there is no jig insertion loss
- Jig leakage around the sample may further limit the dynamic range – but this effect is not seen in the measurement which is usually done with a metal plate. With a real sample jig leakage is more of a problem if the surface is non-conductive.

Frequency range

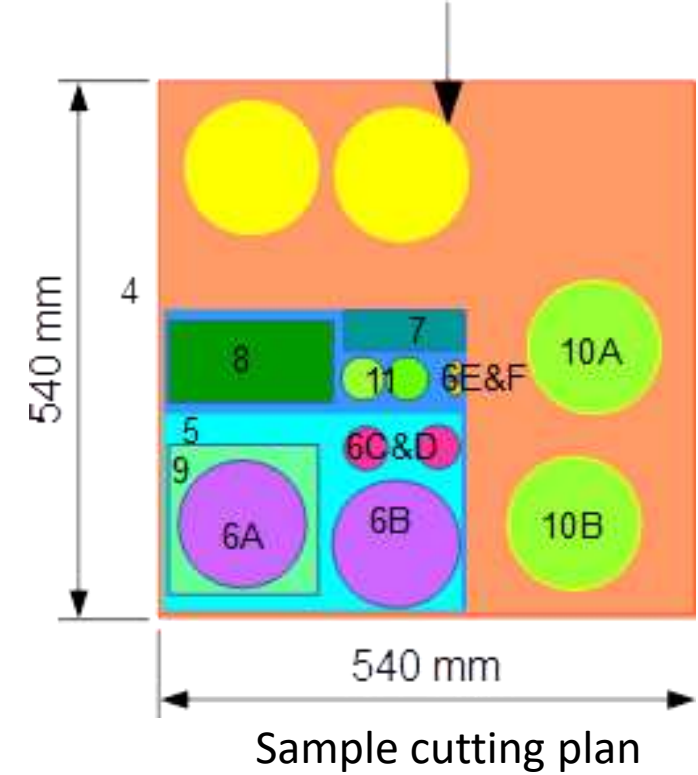
- Freespace:
 - limited by need to have sample many wavelength big
- Absorber box:
 - Currently 1-10GHz (limited by antennas and absorber size)
- Reverberation chamber:
 - >200MHz (depends on chamber size)
- IEEE 299:
 - 50MHz – 10GHz (Depends on chamber and setup)
- TEM-T
 - 10MHz-1GHz
- Coax ASTM
 - dc – 18GHz (needs smaller coax for HF, sample surface may limit LF)

Sample preparation

- Most methods require that the sample be cut to size and drilled to match mounting holes
 - AB & FS are simpler
- Most methods are affected by the surface conductivity – non-conductive surface may cause leakage
 - AB & FS are not, Coax can compensate



Coax samples



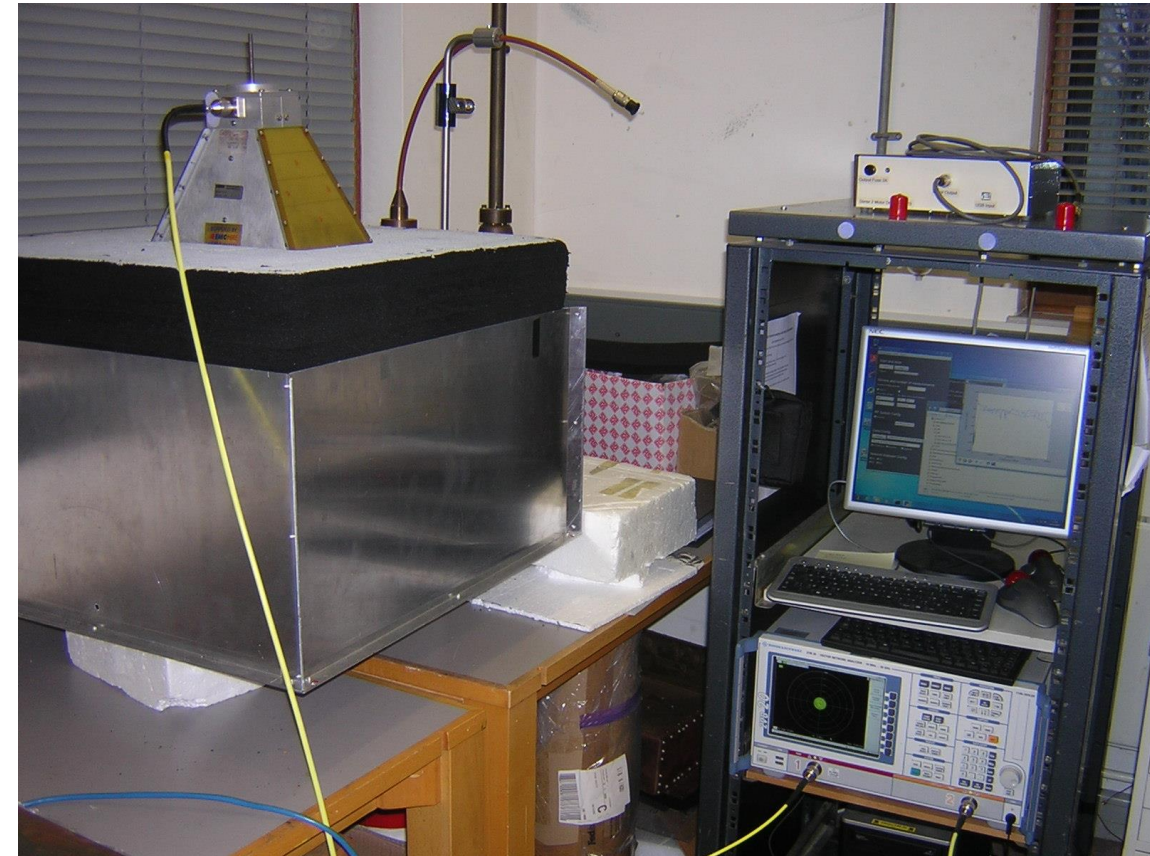
Reverb sample

Anisotropic materials

- Some methods average over a number of polarizations so cannot detect anisotropy in the sample:
 - Coax, Reverberation chamber
- Reverberation chamber averages over all angles of incidence
- Other methods have a single angle of incidence
 - Free-space, Absorber box, Coax, TEM-T, Dual waveguide, Dual TEM, IEEE-299
 - These methods can measure SE for different sample orientations and so quantify anisotropy

Equipment required

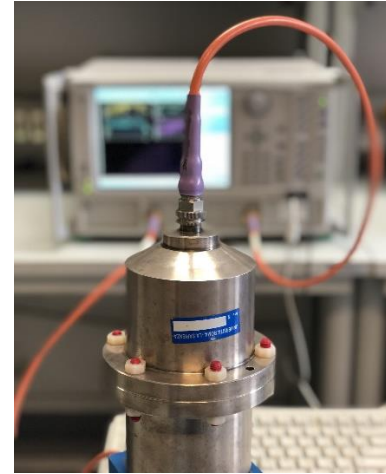
- All use similar instruments
 - Vector network analyser (VNA) or,
 - Signal generator and receiver
- Just different test jigs
- Actual performance depends on jig and instruments:
 - Source power
 - Receiver noise-floor
 - Jig and cable leakage
 - Jig leakage may depend on sample



Absorber Box measurement setup:
VNA, cables, 2 antennas, Absorber box

Physical size

- Chamber methods
 - Several meters in each dimension
- Free space method
 - A few wavelengths (~ 1m cube here)
- Absorber box
 - 600mm cube for 1-10GHz range
- Coax
 - 100 diameter x ~300mm long
- TEM cells
 - ~300 mm cube



Coaxial jig



IEEE 299 dual chamber setup



Dual TEM cell

What is measured?

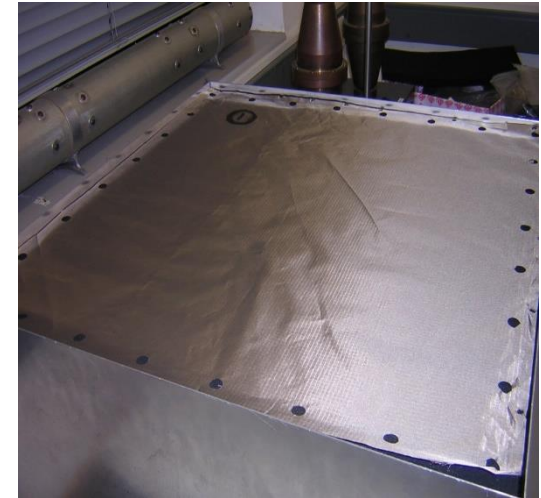
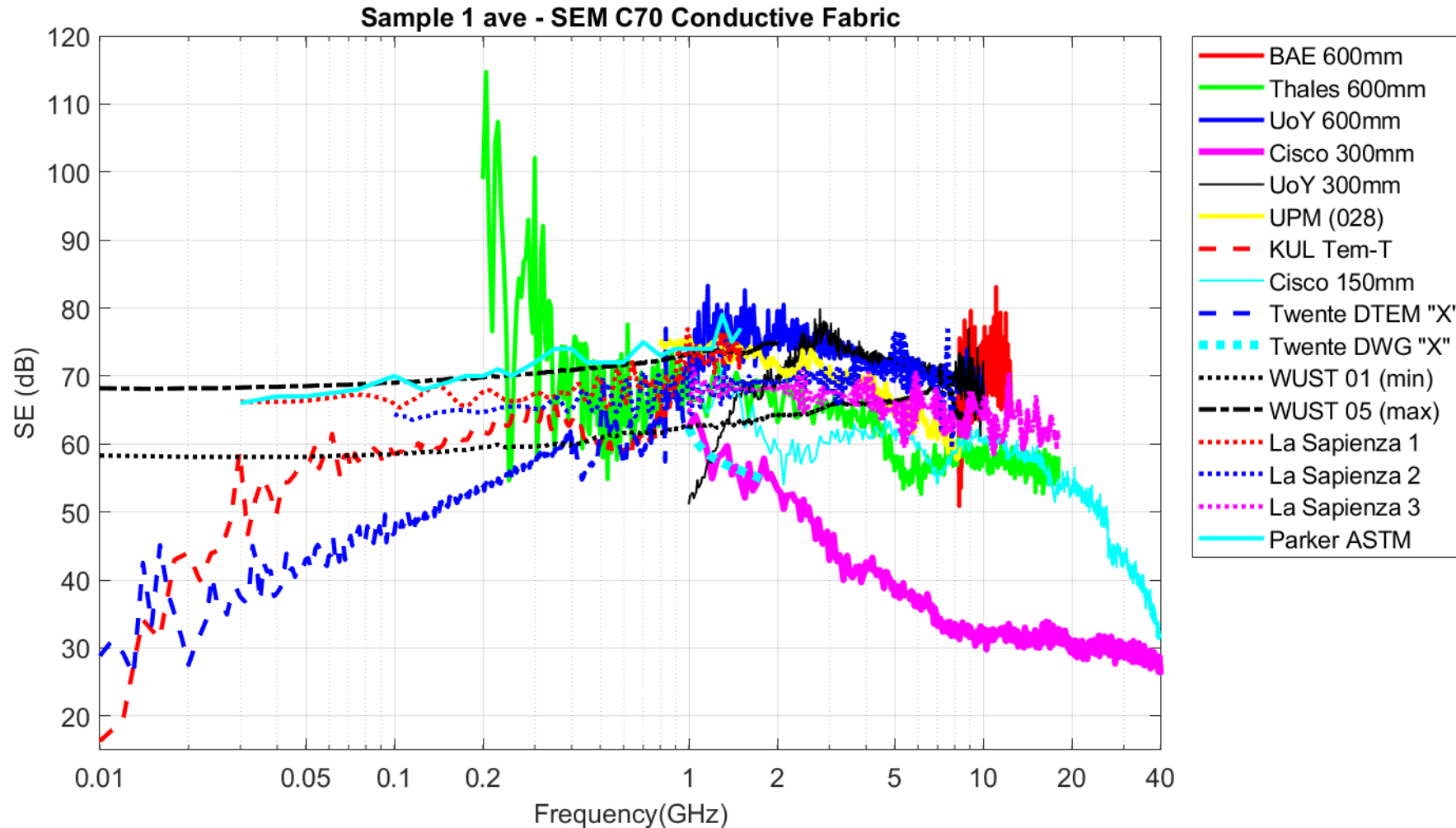
- Plane wave, Waveguide mode, Reverberant field
- Other?
- How should we compare these ?
 - In this presentation the SE measured on the single polarisation jigs (FS,AB, TEM-X,DWG) was averaged over both polarisations for comparison with the methods which measure over a range of polarisations and angles:

$$\overline{SE} = \frac{1}{\frac{1}{2\pi} \int_0^{2\pi} \sqrt{\left(\frac{\cos \theta}{SE_x}\right)^2 + \left(\frac{\sin \theta}{SE_y}\right)^2} d\theta} \text{ where } SE_x = \frac{E_{0x}}{E_{tx}} \text{ is the ratio of incident } (E_{0x}) \text{ to transmitted } (E_{tx}) \text{ field in one}$$

polarisation and $SE_y = \frac{E_{0y}}{E_{ty}}$ is the ratio measured in the orthogonal polarisation.

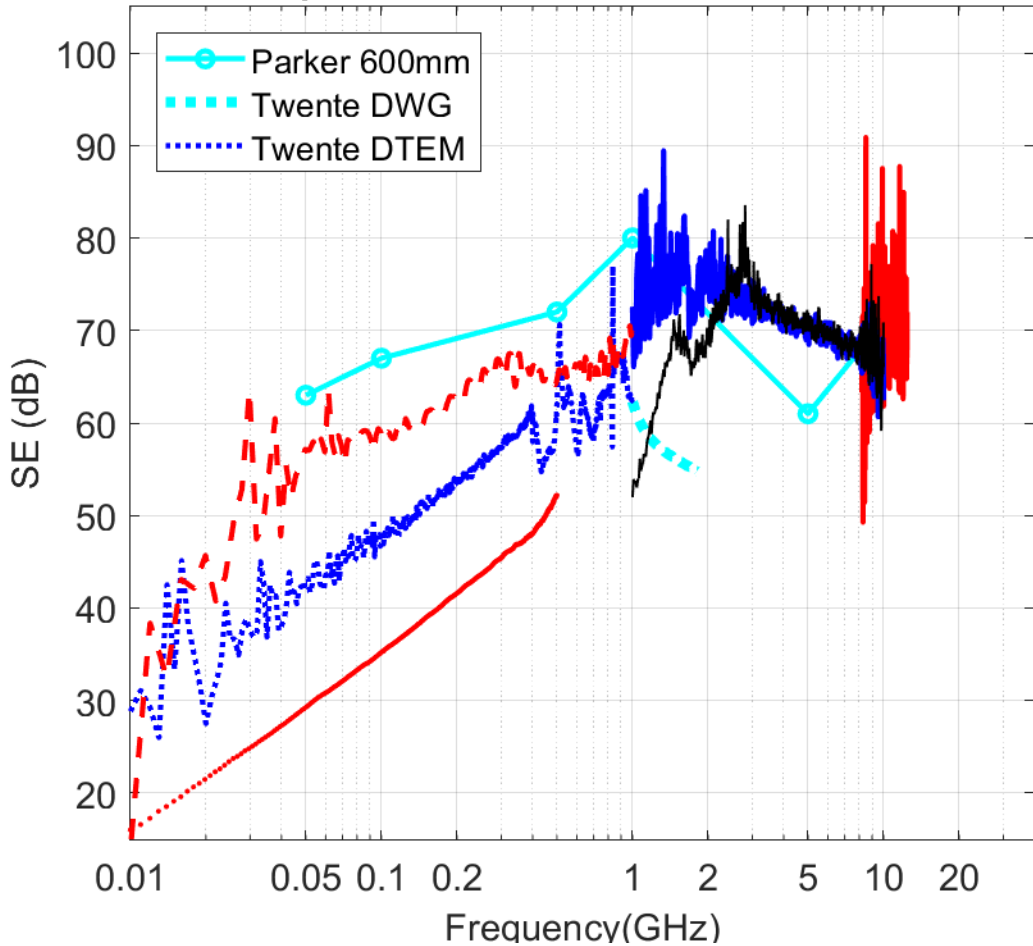
- For Coax, and reverb the values are presented as measured.

Results comparison

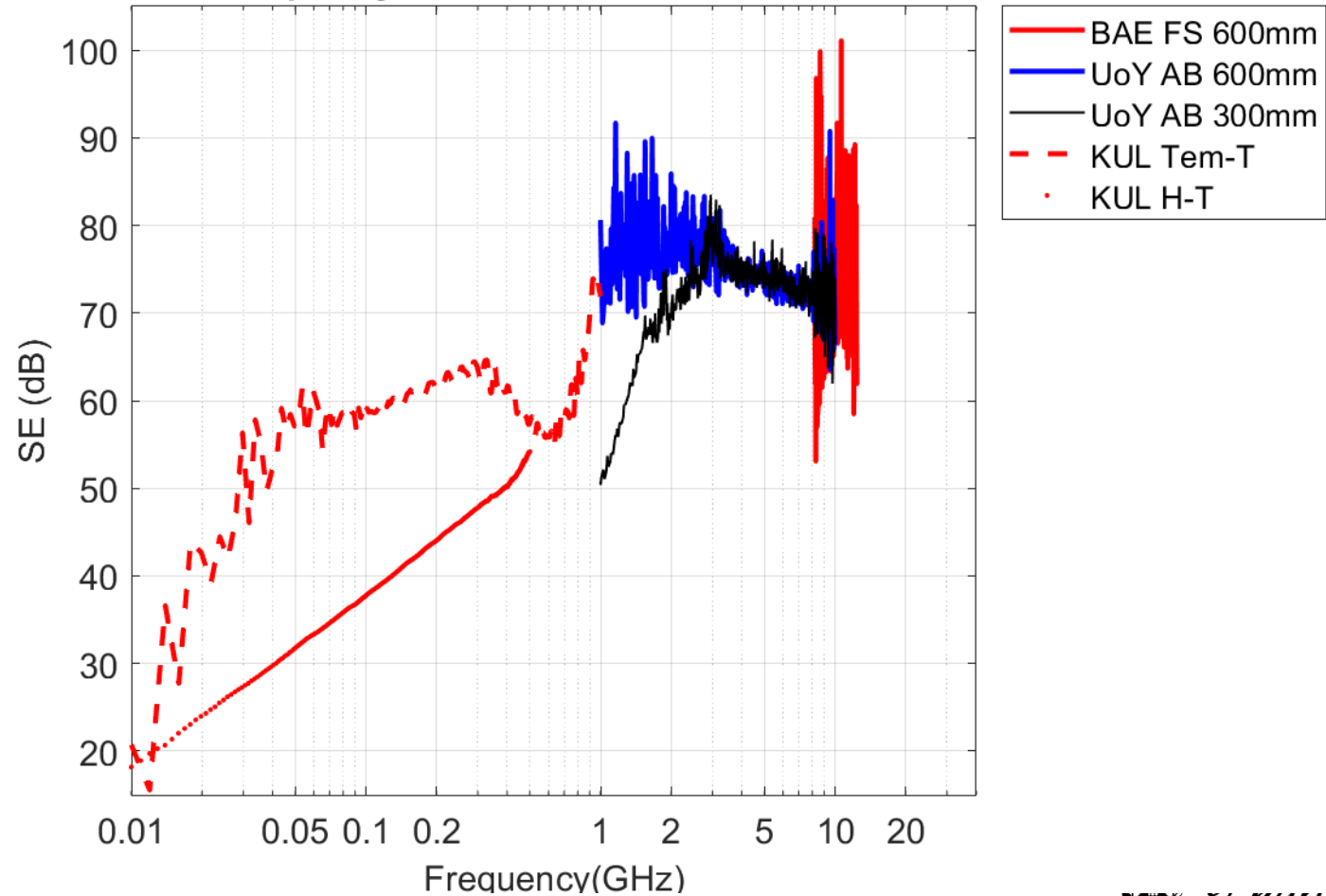


Results comparison

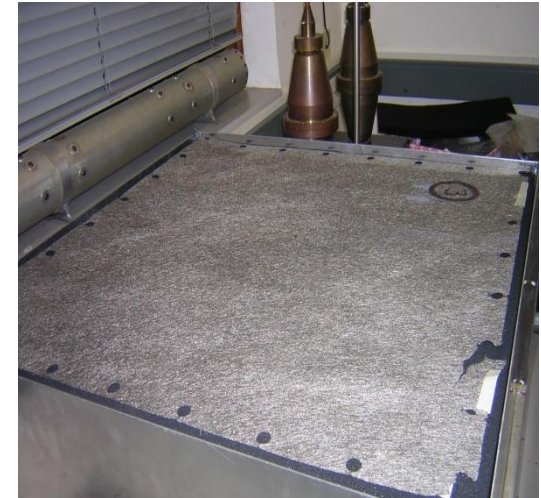
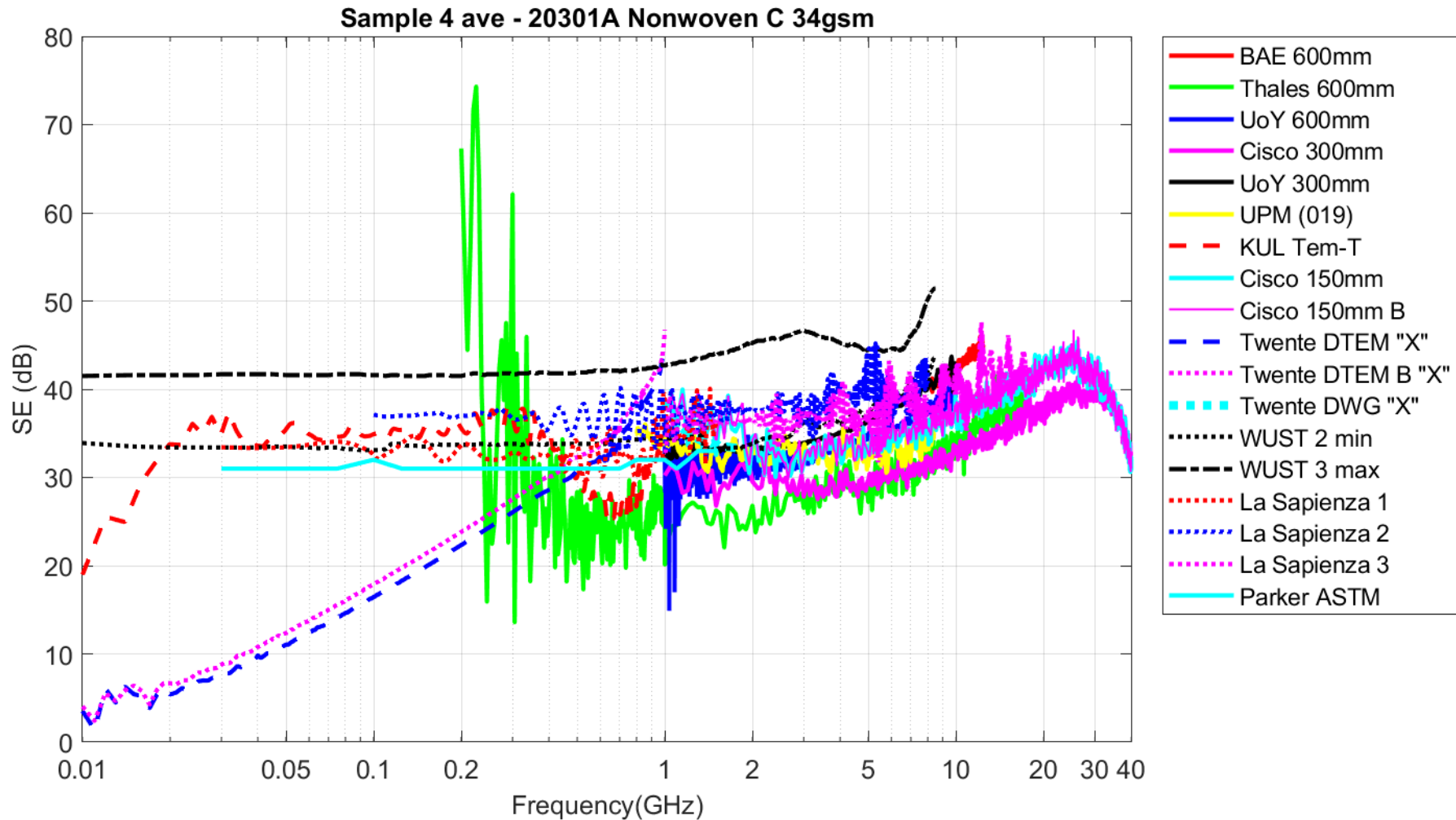
Sample 1 x - SEM C70 Conductive Fabric



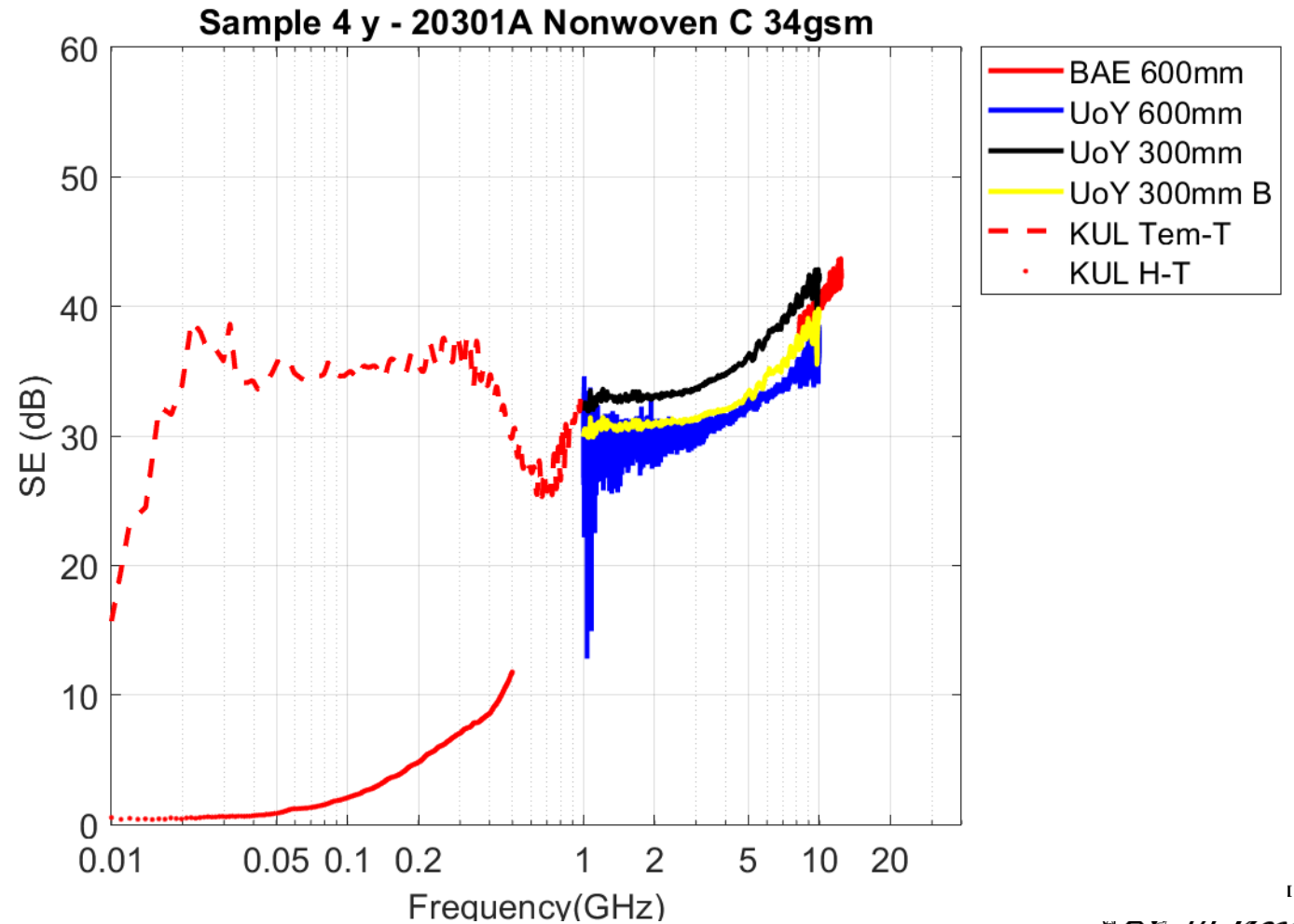
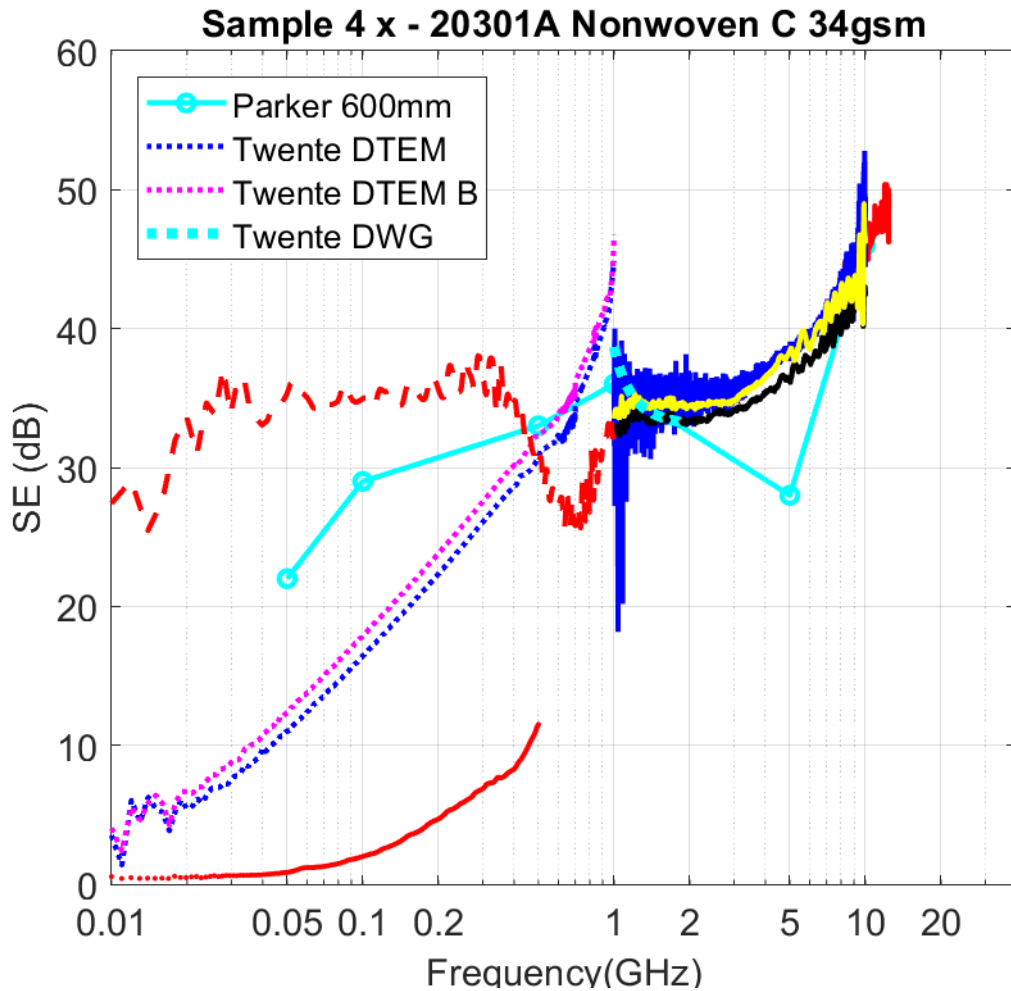
Sample 1 y - SEM C70 Conductive Fabric



Results comparison

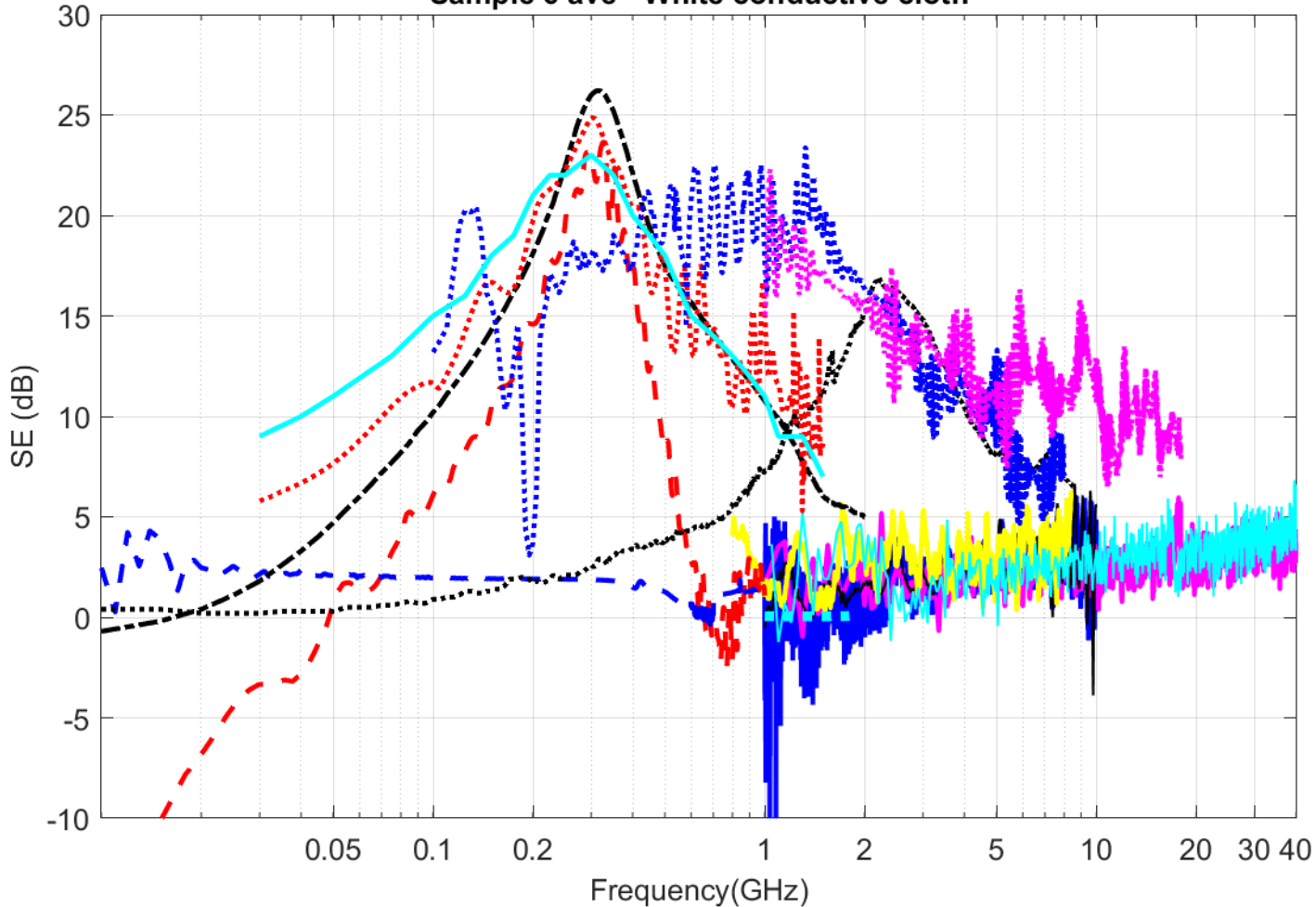


Results comparison



Results comparison

Sample 6 ave - White conductive cloth

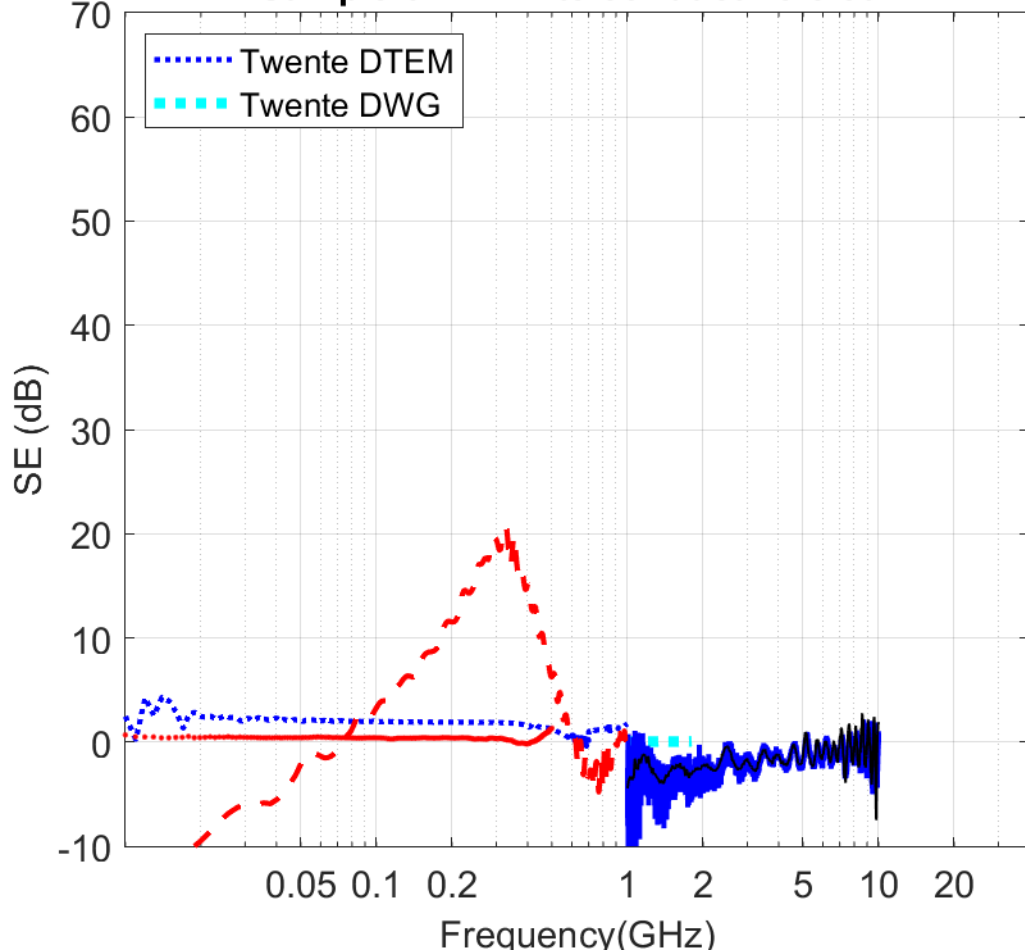


- UoY 600mm
- Cisco 300mm
- UoY 300mm
- UPM (001)
- KUL Tem-T
- Cisco 150mm
- Twente DTEM "X"
- Twente DWG "X"
- WUST 3 min
- WUST 5 max
- La Sapienza 1
- La Sapienza 2
- La Sapienza 3
- Parker ASTM

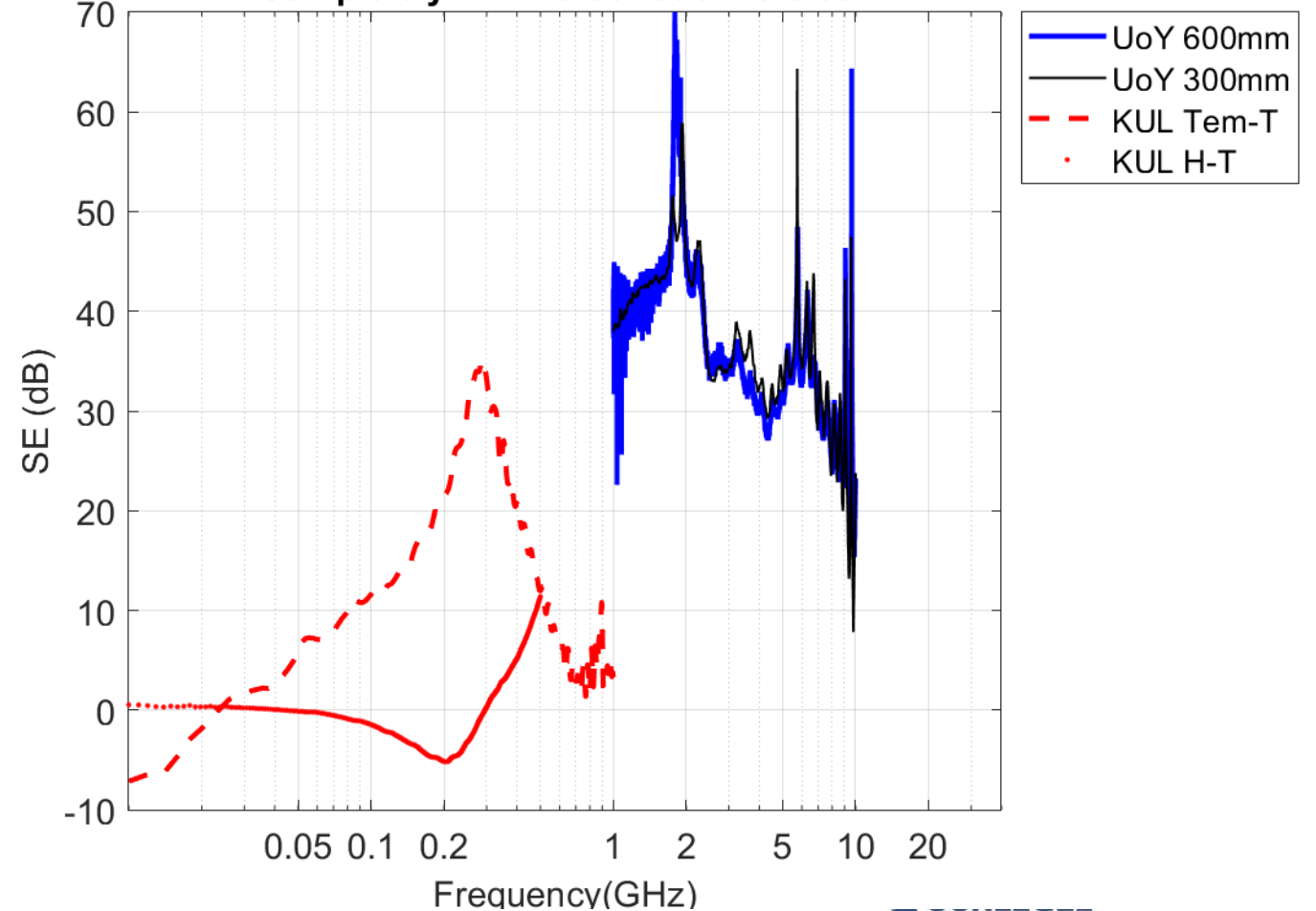


Results comparison

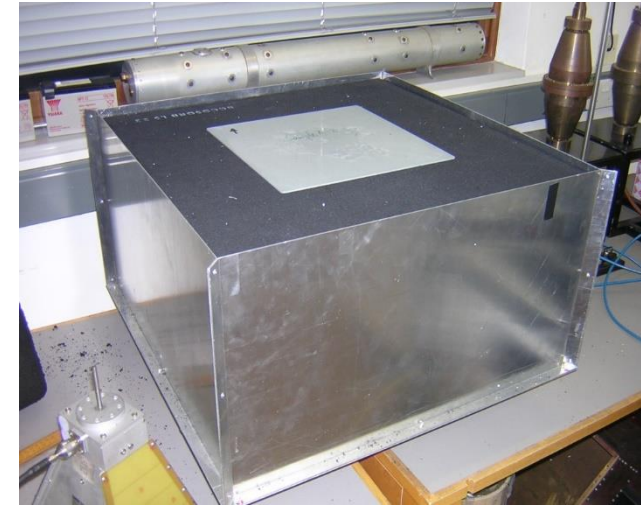
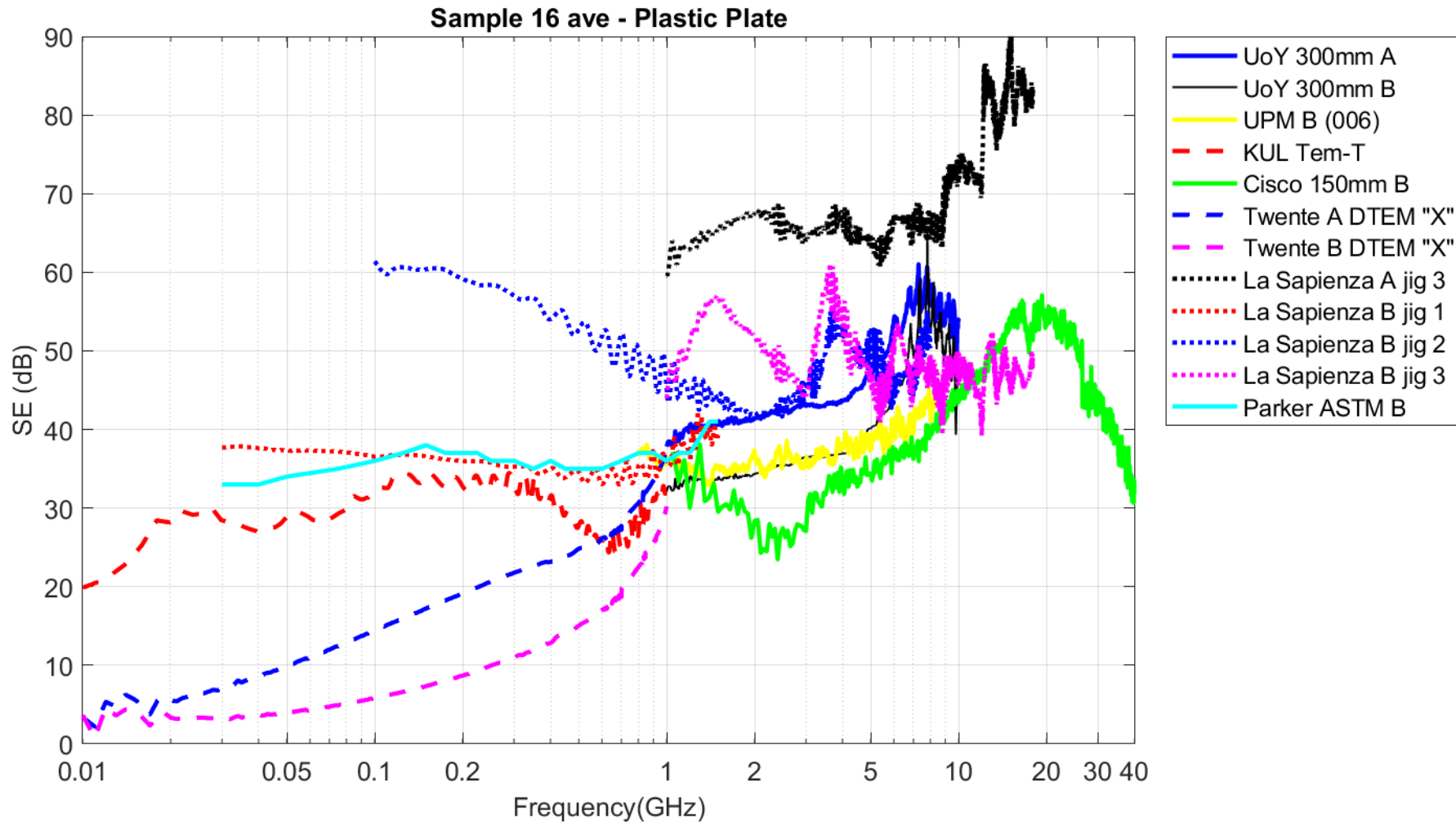
Sample 6 x - White conductive cloth



Sample 6 y - White conductive cloth



Results comparison



Conclusions

- No best method
 - Material dependent
 - Test results needs to compared to Dynamic range
 - Dynamic range is limited in high frequencies (>20GHz)
 - Jig leakage limits the accuracy
 - Some significant variation between different samples of the same material
 - Some strange jig dependent behaviours for some materials.
-
- SE measurements are not easy!